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(12) **United States Design Patent**
Teranishi et al.

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- (54) **PROBE PIN**
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- (73) Assignee: **OMRON Corporation**, Kyoto (JP)
- (**) Term: **15 Years**

8,669,774 B2 * 3/2014 Kato G01R 1/06722
324/755.01
8,808,038 B2 * 8/2014 Hwang G01R 1/06722
439/66
9,130,290 B2 * 9/2015 Sakai H01R 13/2428

(Continued)

FOREIGN PATENT DOCUMENTS

KR 30-0653160 7/2012
KR 300735080 3/2014
WO 2007/097559 A1 8/2007

OTHER PUBLICATIONS

Search Report dated Sep. 11, 2015 for Taiwanese Application No. 104302991 with Translation.

(Continued)

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- (51) **LOC (10) Cl.** **10-04**
- (52) **U.S. Cl.**

USPC **D10/80**

- (58) **Field of Classification Search**
- USPC D10/78, 80; D13/133, 154
- CPC G01R 1/067; G01R 1/06705; G01R 1/06711; G01R 1/06716; G01R 1/06722; G01R 1/06727; G01R 1/06733; G01R 1/06738; G01R 1/06744; G01R 1/0675; G01R 1/06766; G01R 1/06772; G01R 1/06777; G01R 1/06783; G01R 1/0678
- See application file for complete search history.

- (56) **References Cited**

U.S. PATENT DOCUMENTS

D133,267 S * 8/1942 Burt 439/883
D229,184 S * 11/1973 Brown et al. D10/103
D325,564 S * 4/1992 Lemke D13/154
D507,197 S * 7/2005 Sun D10/72
D662,895 S * 7/2012 Kimura D13/154
D665,744 S * 8/2012 Yamauchi D13/133
D665,745 S * 8/2012 Yamauchi D13/133
8,366,496 B2 * 2/2013 Hsu G01R 1/0466
439/66
8,460,010 B2 * 6/2013 Kimura G01R 1/06722
439/66

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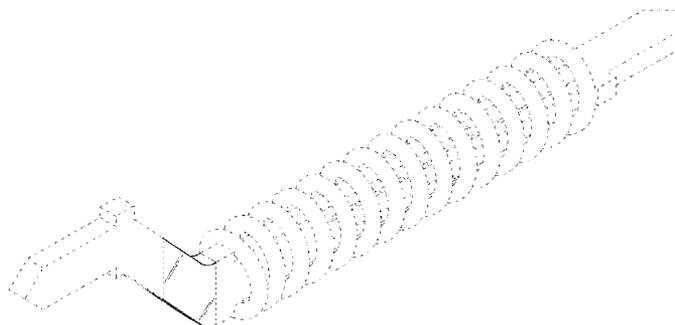
- (57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. 1 is a top front perspective view of a probe pin showing our new design;
FIG. 2 is a front view thereof;
FIG. 3 is a rear view thereof;
FIG. 4 is a left side view thereof;
FIG. 5 is a right side view thereof;
FIG. 6 is a top view thereof; and,
FIG. 7 is a bottom view thereof.
The dashed broken lines in the figures show portions of the probe pin that form no part of the claimed design.
The dot-dash broken lines in the figures show boundaries of the claimed design.
The shade lines in the figures show contour and not surface ornamentation.

1 Claim, 4 Drawing Sheets



(56)

References Cited

OTHER PUBLICATIONS

U.S. PATENT DOCUMENTS

D749,968 S * 2/2016 Huang D10/77
D750,987 S * 3/2016 Huang D10/80
9,322,846 B2 * 4/2016 Sakai G01R 1/06716

U.S. Appl. No. 29/528,956, filed Jun. 2, 2015; Teranishi et al.
U.S. Appl. No. 29/528,958, filed Jun. 2, 2015; Teranishi et al.
Korean Office Action issued in KR Appl. No. 30-2015-0027089.

* cited by examiner

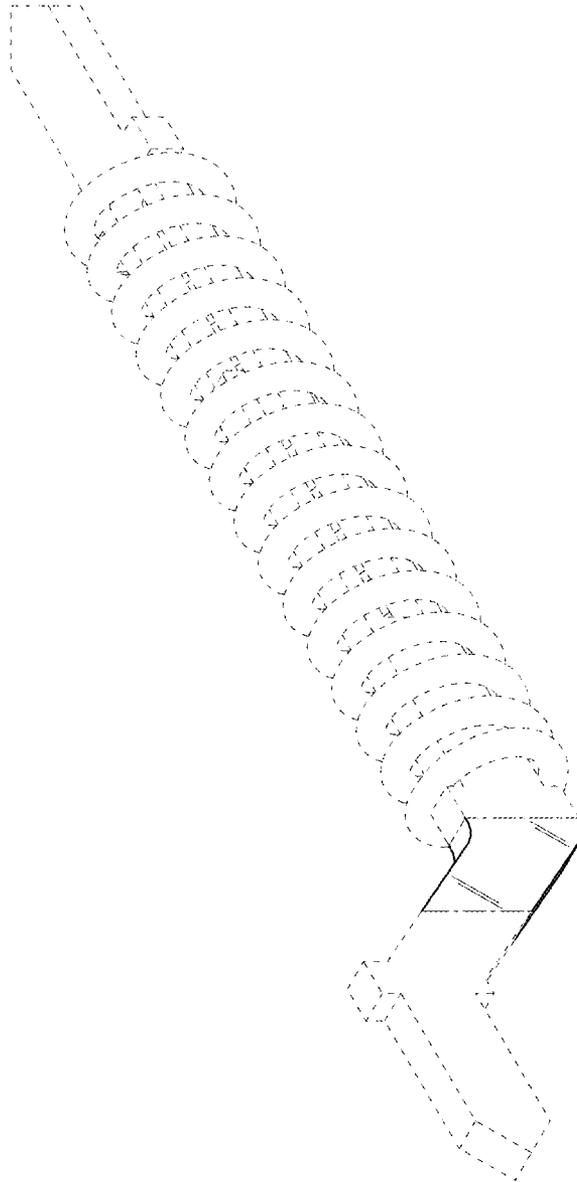
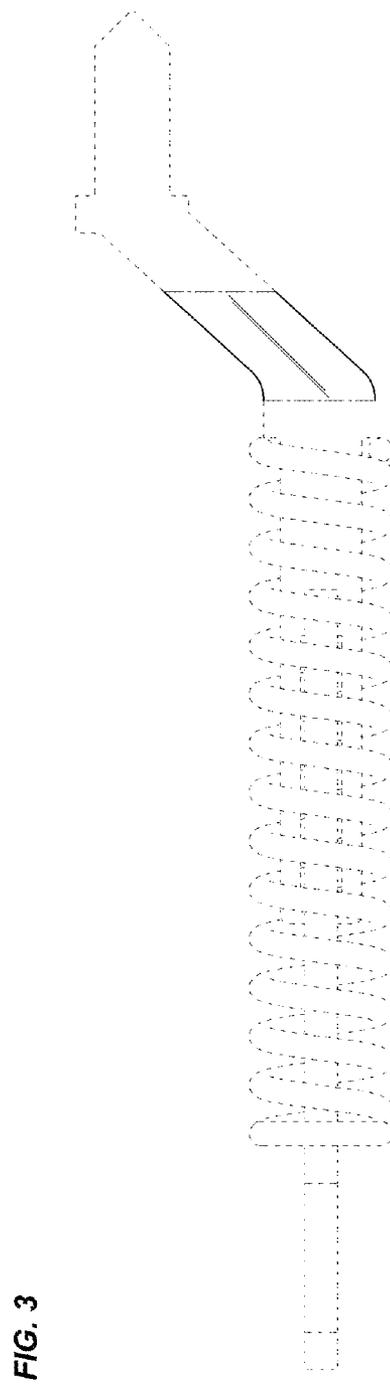
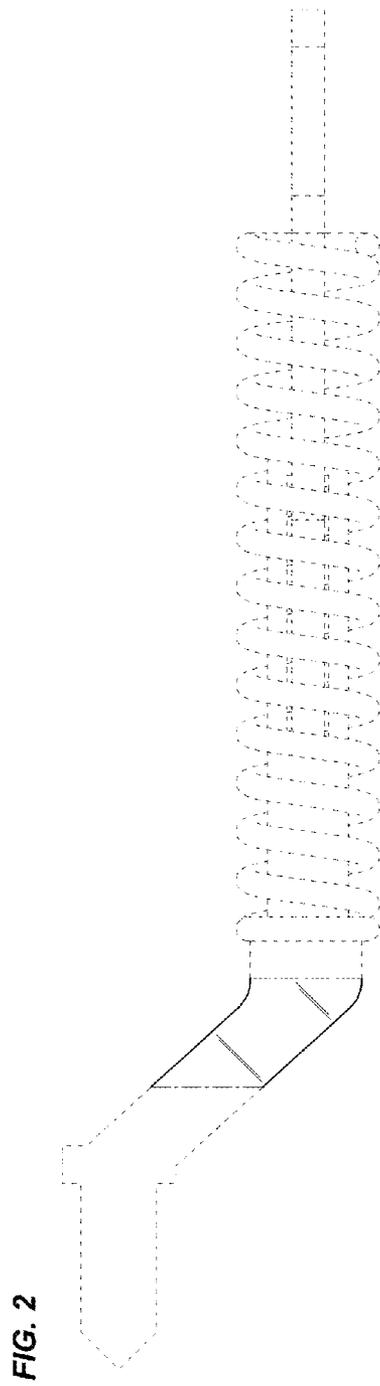


FIG. 1



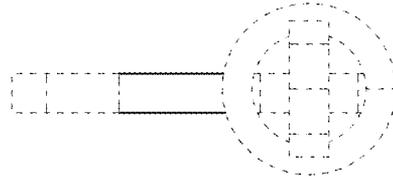


FIG. 5

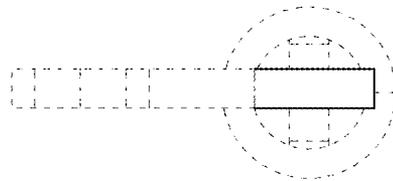


FIG. 4

FIG. 6

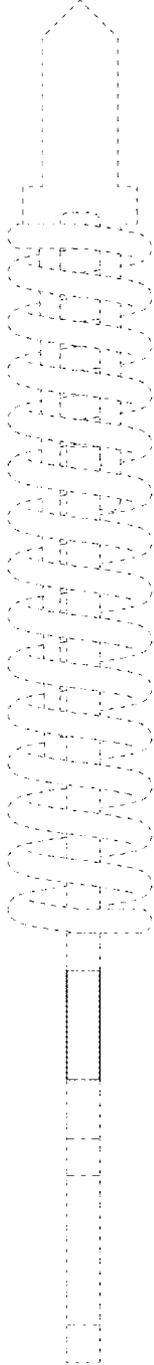


FIG. 7

